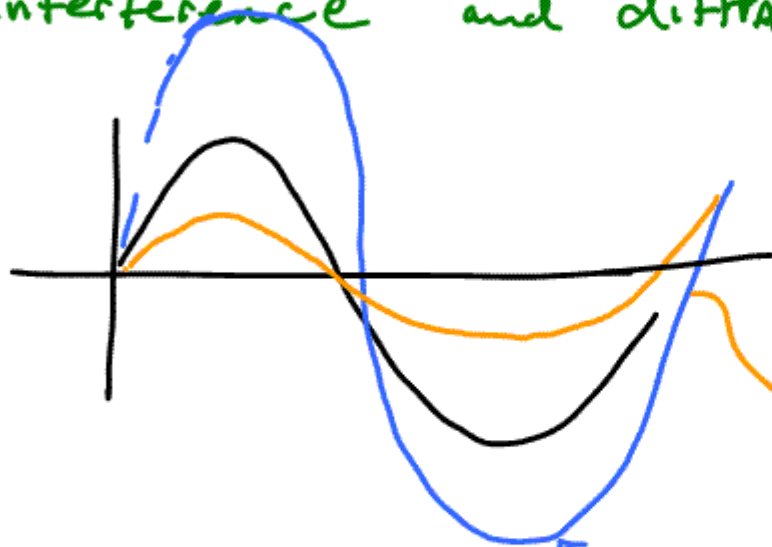


Physics 142 - December 6, 2005

Physical Optics

Interference and diffraction



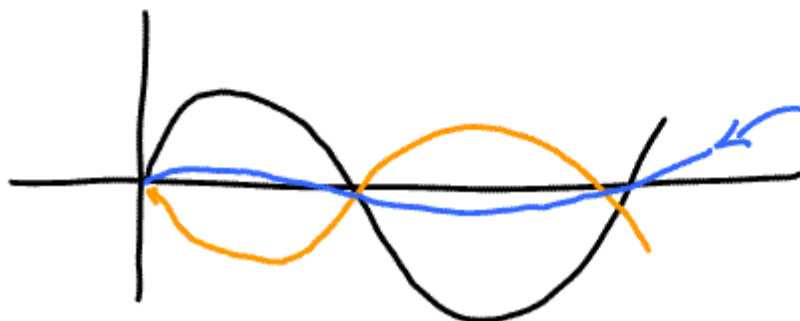
$$\vec{E}_1 = \vec{E}_{01} \sin(\omega t - k z)$$

$$\vec{E}_2 = \vec{E}_{02} \sin(\omega t - k z + \delta)$$

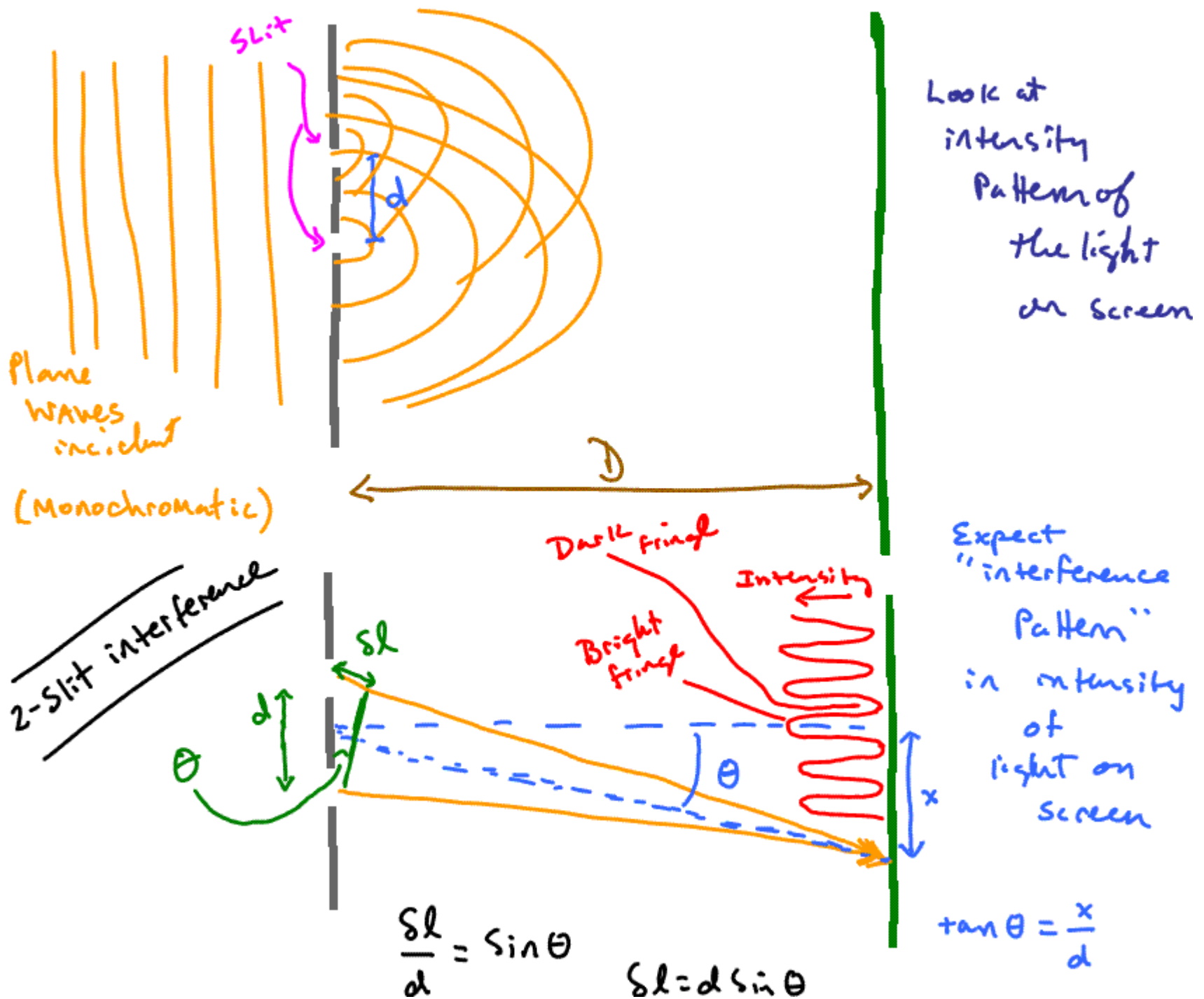
$\delta = 0$ in phase

Constructive interference

if $\delta = \pi$



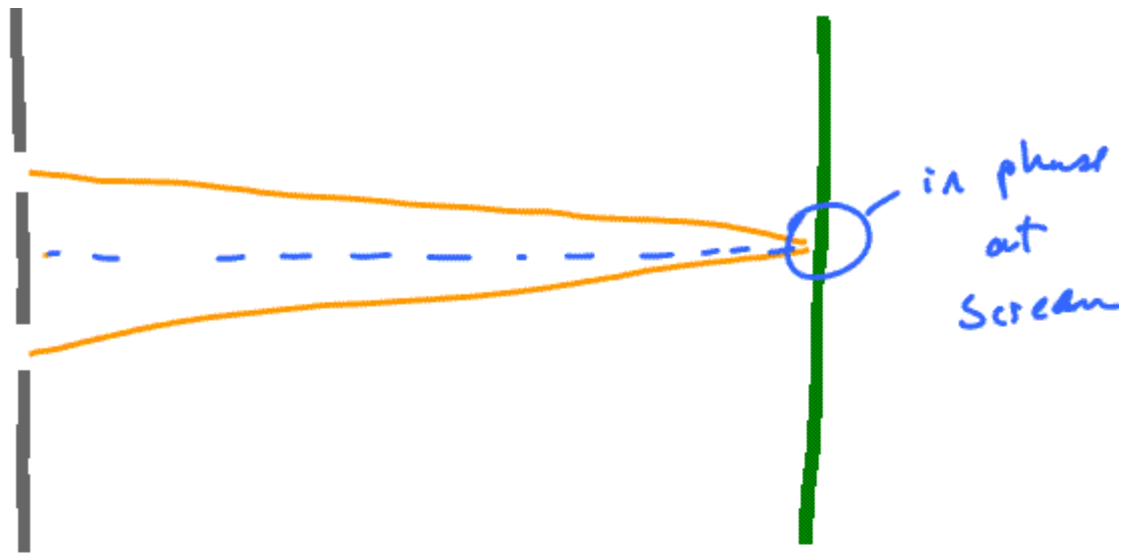
Destructive interference



Look at intensity pattern of the light on screen

Expect "interference pattern" in intensity of light on screen

2-slit interference



Constructive Interference

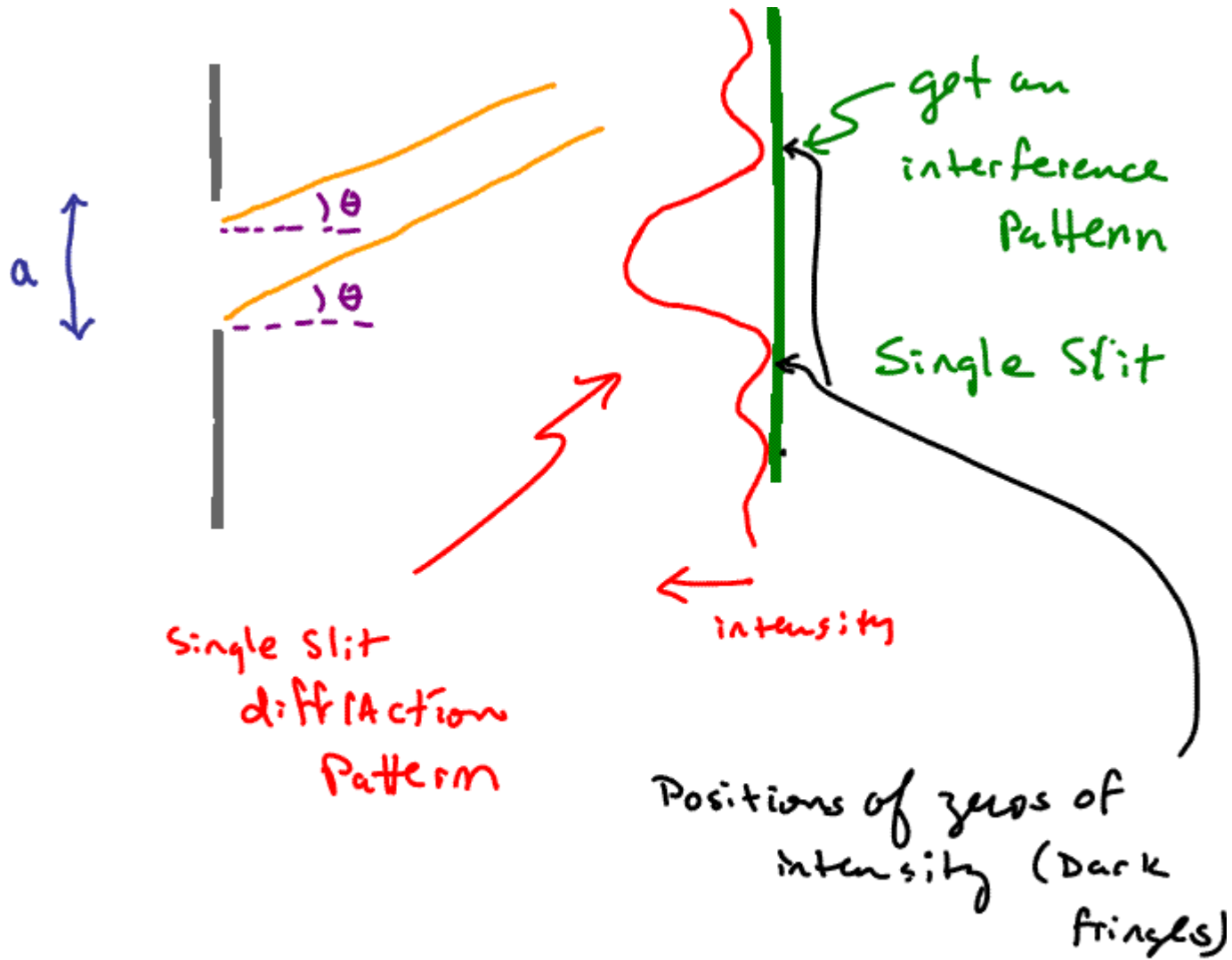
$$d \sin \theta = m \lambda \quad m = 0, 1, 2, \dots$$

bright fringes on screen

$$d \sin \theta = m \lambda$$

Destructive Interference

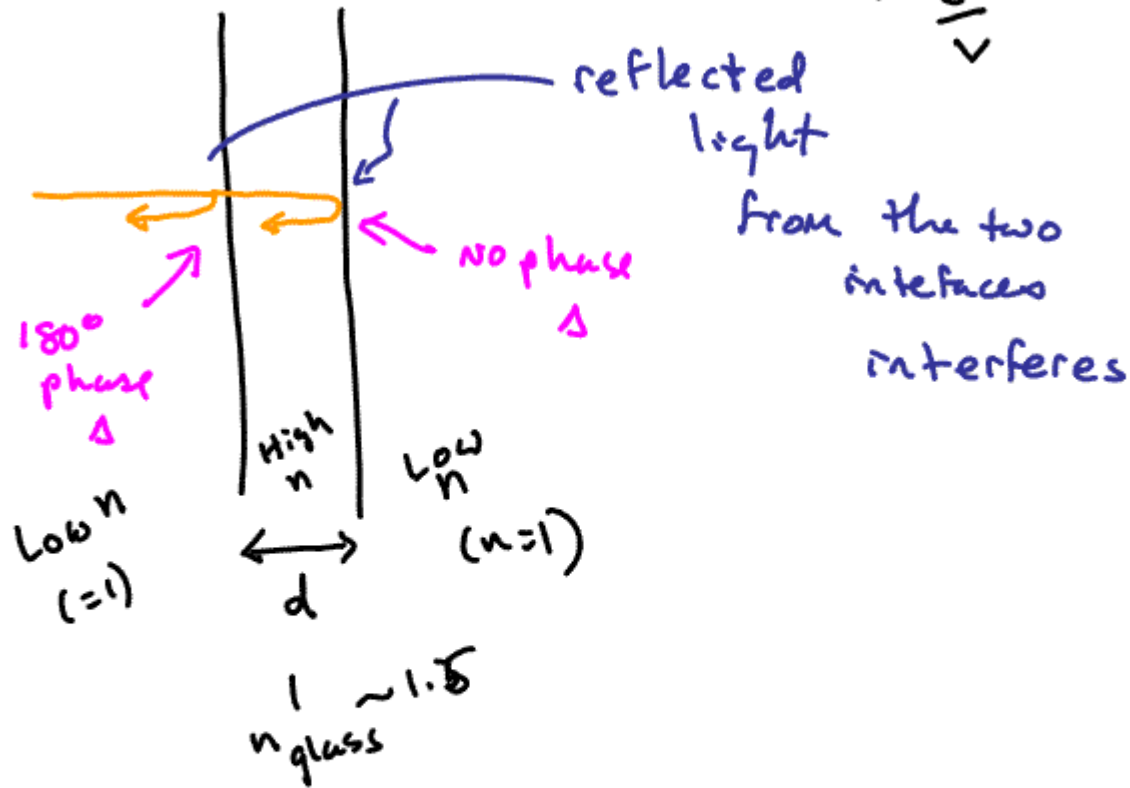
$$d \sin \theta = (m + \frac{1}{2}) \lambda \quad m = 0, 1, 2, \dots$$



$$\sin \theta = \frac{\lambda}{a}$$

Thin film interference

$$n \equiv \text{index of refraction} \\ = \frac{c}{v}$$



High n to low $n \Rightarrow$ no phase change upon reflection

Low n to High $n \Rightarrow$ 180° phase change upon reflection

$2d = m \lambda_n$
 extra distance
 Traveled by wave
 penetrating glass

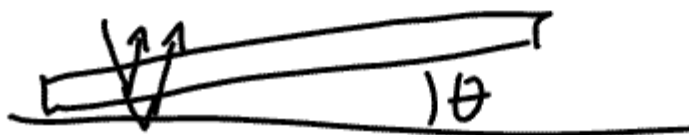
λ in the material $\lambda_n = \frac{\lambda}{n}$
 $m = 1, 2, 3, \dots$

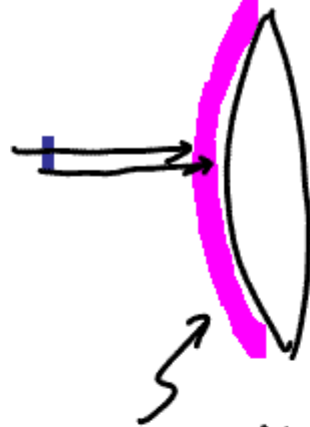
condition for
destructive
 interference

(recall 180° phase Δ for
 one ray)

Constructive interference

$$2d = (m + \frac{1}{2}) \lambda_n = (m + \frac{1}{2}) \frac{\lambda}{n}$$





anti-reflective coating

coating MgF_2

reduce reflection
camera lens

central $\lambda = 550 \text{ nm}$
(visible)

How thick should coating be to minimize
reflection at $\lambda = 550$



180° phase shift
Both
interfaces

minimum
(Destruct)

$$2d = (m + \frac{1}{2}) \lambda_n$$

$$m = 0, 1, 2, \dots$$

$$\lambda_n = \lambda / n$$

Thinnest possible film

$$2d = (m + \frac{1}{2}) \lambda_n$$

$$m=0$$

$$2d = \frac{1}{2} \lambda_n = \frac{1}{2} \frac{\lambda}{n}$$

$$d = \frac{\lambda}{4n} = 100 \text{ nm}$$

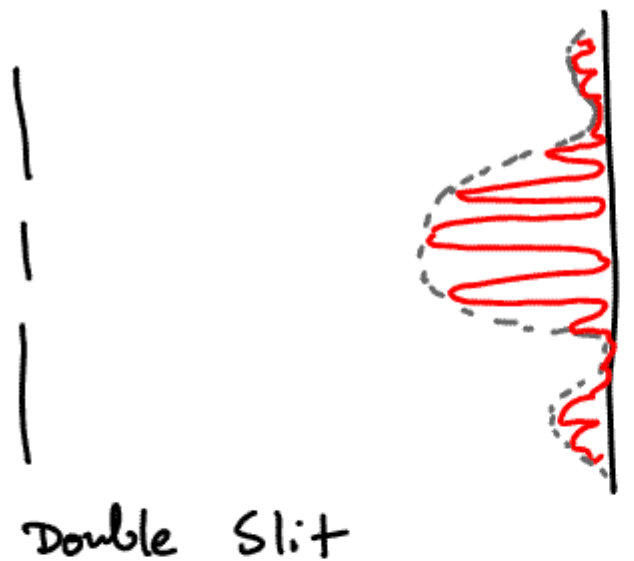
Return to
Diffraction



2-slit int pattern



single slit Diffraction



Double Slit

in reality

Diffraction + interference

Cent Diff. Max.

$$\text{Width} \sim \frac{\lambda}{a} = \sin \theta$$



multiple Slits

multiple Slits



ruled grating

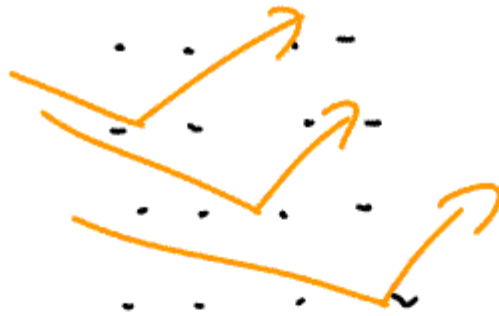


Intensity Maxima

$$d \sin \theta = m \lambda$$

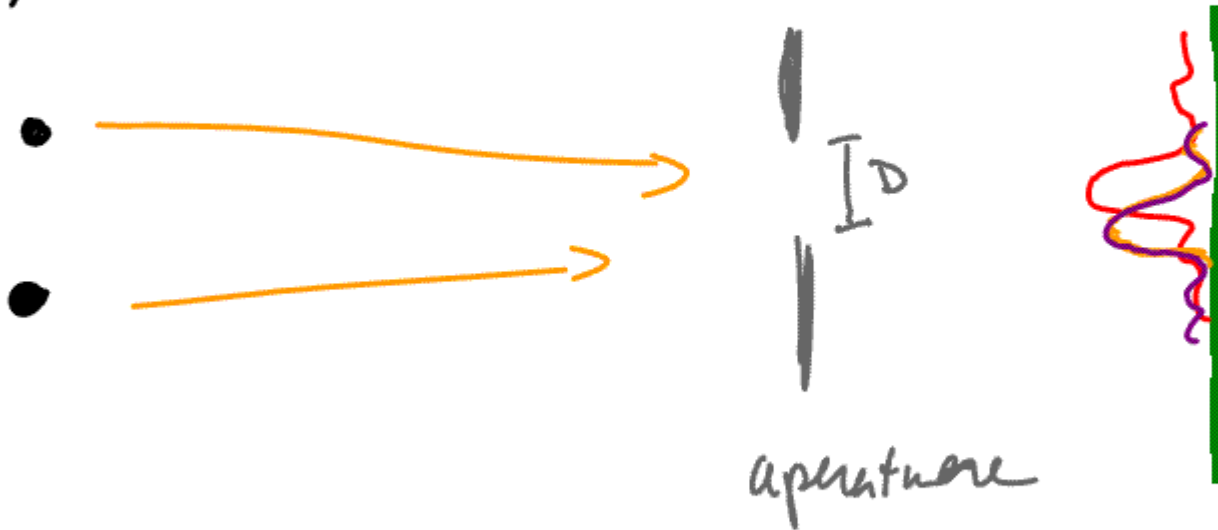
order

X-ray Diffraction

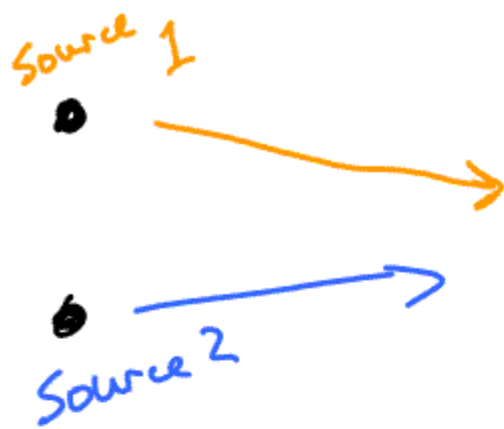


Pattern

2 pt sources



Central Max of one source
 \geq the dist to the 1st Min of
the other source



Rayleigh's
Criterion

Central max for Source 2

falls on 1st minimum for Source 2

Say this is the minimum

resolvable separation

Thin slit

$$\sin \theta = \frac{\lambda}{a}$$

posn of
1st Min

→ Circular
Aperture

$$\sin \theta = 1.22 \frac{\lambda}{a}$$

or

$$1.22 \frac{\lambda}{D}$$

small θ

$$\sin \theta \sim \theta = 1.22 \frac{\lambda}{D}$$